

Rewriting Flash Memories by Message Passing

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Main Limitation Of Flash: Erase Before Write

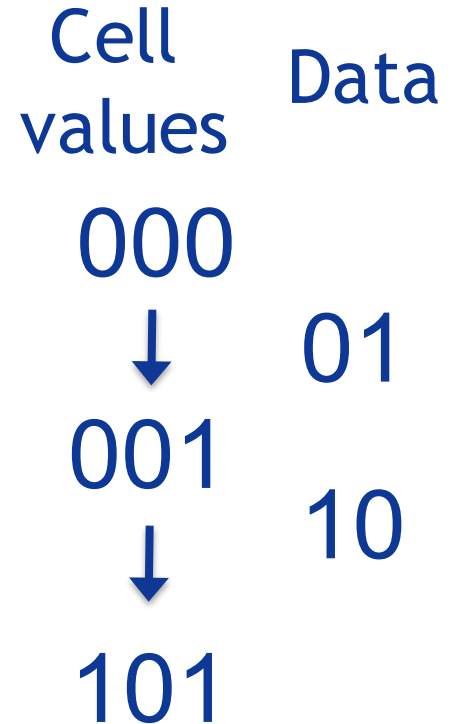
- Problem:
 - Limits endurance, speed and power efficiency
- Potential **solution**: write without erasure = rewrite
- Tool: Write-Once Memory (WOM) codes

What are WOM codes?

- Proposed by Rivest, Shamir '82

Data to Store	1 st -write code word	2 nd -write code word
00	000	111
01	001	110
10	010	101
11	100	011

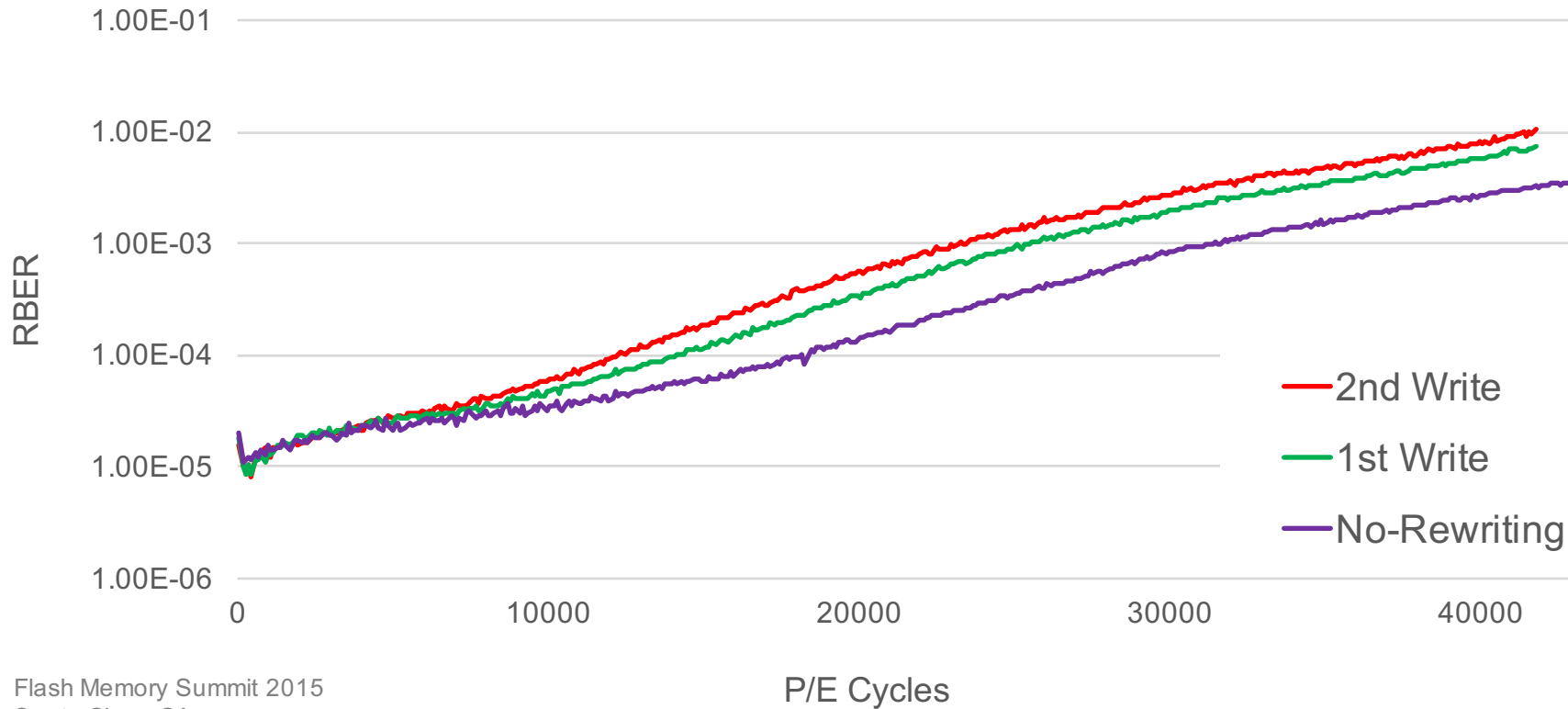
- Allow writes without erase



Challenges of WOM codes

1. Interference
2. Storage overhead
- 3. Circuit complexity**
 - More?

Interference



Storage Overhead

- **Minimized** by capacity-achieving WOM codes
 - Entropy polarization: Burshtein & Strugatski '13
 - Randomness extractors: Gabizon & Shaltiel '12, Shpilka '13
- **Reduce** over-provisioning and write amplification
 - Odeh & Cassuto '14, Yadgar et al. '15

- **Problem:**
 - good WOM codes are hard to implement
- Proposed **solution**: “LDPC-like” WOM codes.
- **Advantages:**
 1. LDPC-like complexity
 2. Can share circuit modules with ECC

Construction

G = generator matrix of LDPC code

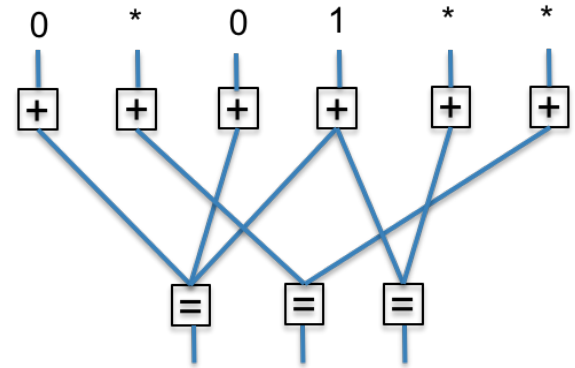
Encoding: find x for which

1. $x \geq s$ (can write without erase)
2. $m = Gx^T$ (word represents the message)

How to find x fast:

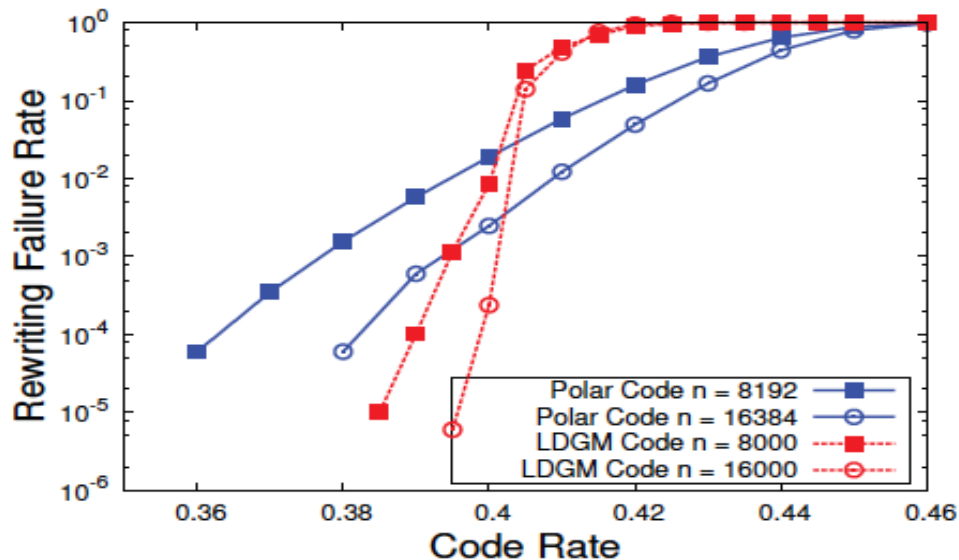
- **Message passing** on sparse Tanner graph
- Algorithm by Martinian, Yedidia '02
- Originally for data compression

Decoding: $m = Gx^T$



Rewriting Failures

- Message-passing encoder sometimes **fails**
 - Failures are **not as critical** as in ECC => Failure rate can be higher
 - Failure rate depends on code rate
 - **Example:** rewriting an Invalid page
 - $\frac{1}{2}$ of the cells cannot be rewritten
- ⇒ WOM code rate cannot exceed $\frac{1}{2}$



Summary

- Main result: “LDPC-like” WOM codes
- Benefit: Extend endurance for low complexity penalty
- Details in ISIT’15 paper:
 - “Rewriting flash memories with message passing”
- Ongoing experiments on flash chips